

INTEGRATED DIGITAL SERVICES TERMINAL

METALLIC ACCESS RELAY CARD

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1. GENERAL		
1.01 This practice provides information about the IDST Metallic Access Relay (MAR) card (part number 090-57002-01).		
1.02 Whenever this practice is reissued, the reason for reissue will be given in this paragraph.		
1.03 The MAR card resides in the MAR1 through MAR6 slots of the IDST Metallic Test Access Shelf.		2.04 Test signals from the S1DN are also sent to the Loop Shelves via these relays. (The modes of these relays are discussed in the next paragraph.) Information on which digroup and channel unit card are to be tested is provided to the Loop Shelves by the MAC card via the serial communication controller.

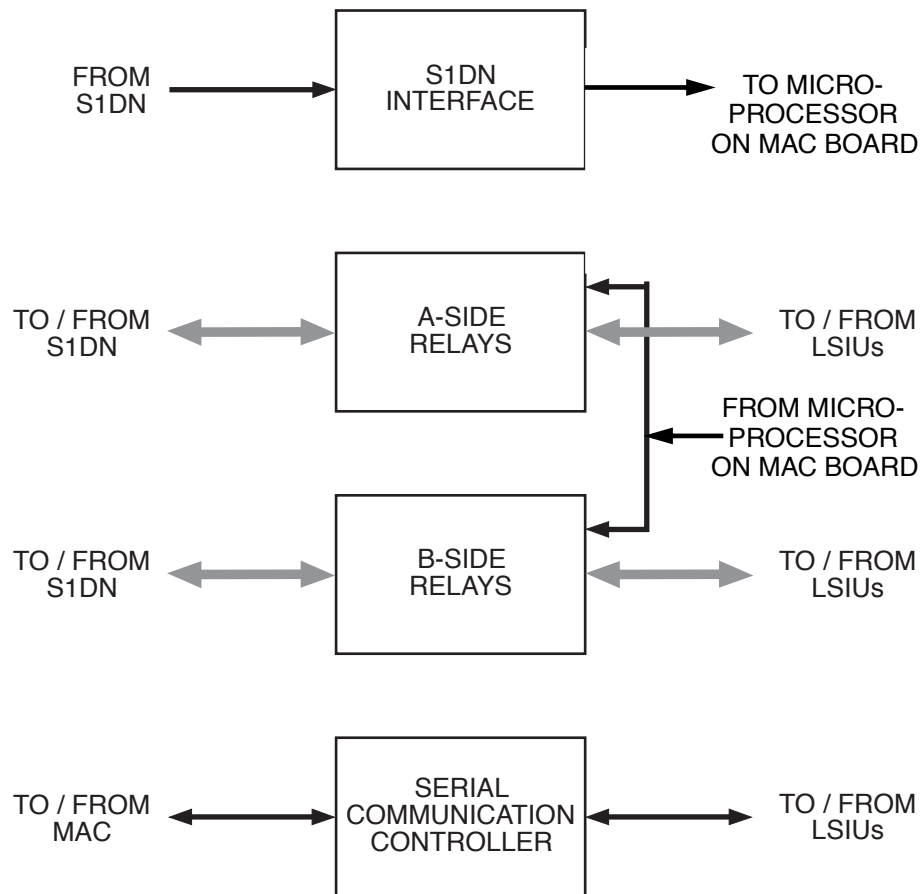


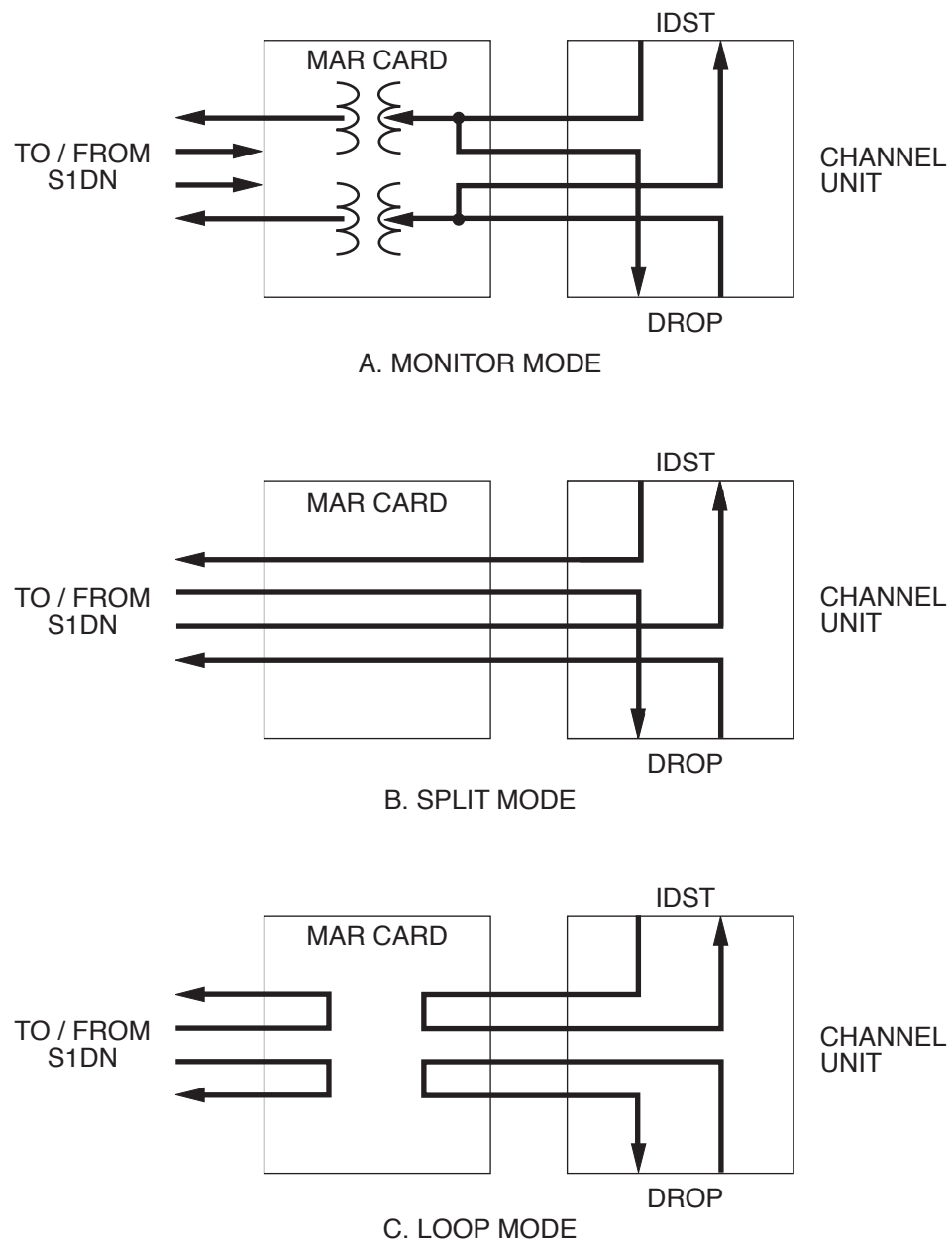
Figure 1. MAR Card Block Diagram

2.05 Figure 2 shows the three modes of the IDST metallic test access relays in the MAR card: monitor, split, and loop. In monitor mode, the signals in both directions in the channel unit are returned to the channel unit so that the signals continue in both directions as if no testing is being performed. In addition, the signal in each direction is monitored through a high-impedance transformer and sent to the S1DN.

2.06 Split mode allows signals to be sent to the channel units in the Loop Shelves. The signals from the

IDST and drop sides are sent to the S1DN and signals from the S1DN and sent to the IDST and drop side of the channel unit card.

2.07 In loop mode, the signals from the S1DN are looped back to the S1DN. The signals from the IDST are looped in the MAR card back to the IDST, and the signals from the drop are looped in the MAR card back to the drop.

**Figure 2. Metallic Test Access Relay Modes**

3. COMMANDS

3.01 The ENT-EQPT command enters the MAR card into the IDST database as follows:

```
ENT-EQPT::MAR-x:<ctag>:::;
```

where x is 1 through 6 (MAR1 through MAR6).

3.02 The RST-EQPT command puts the MAR card in service as follows:

```
RST-EQPT::MAR-x:<ctag>::;
```

where x is 1 through 6 (MAR1 through MAR6).

3.03 The RMV-EQPT command removes the MAR card from service as follows:

```
RMV-EQPT::MAR-x:<ctag>::  
[<mode>],;
```

where x is 1 through 6 (MAR1 through MAR6), and <mode> is NORM (default) or FRCD (forced).

3.04 The DLT-EQPT command deletes the MAR card from the IDST database as follows:

```
DLT-EQPT::MAR-x:<ctag>:::;
```

where x is 1 through 6 (MAR1 through MAR6).

4. FACEPLATE INDICATORS

4.01 Figure 3 is a drawing of the MAR card faceplate indicators.

5. CARD STRAPS

5.01 The MAR card has no straps.

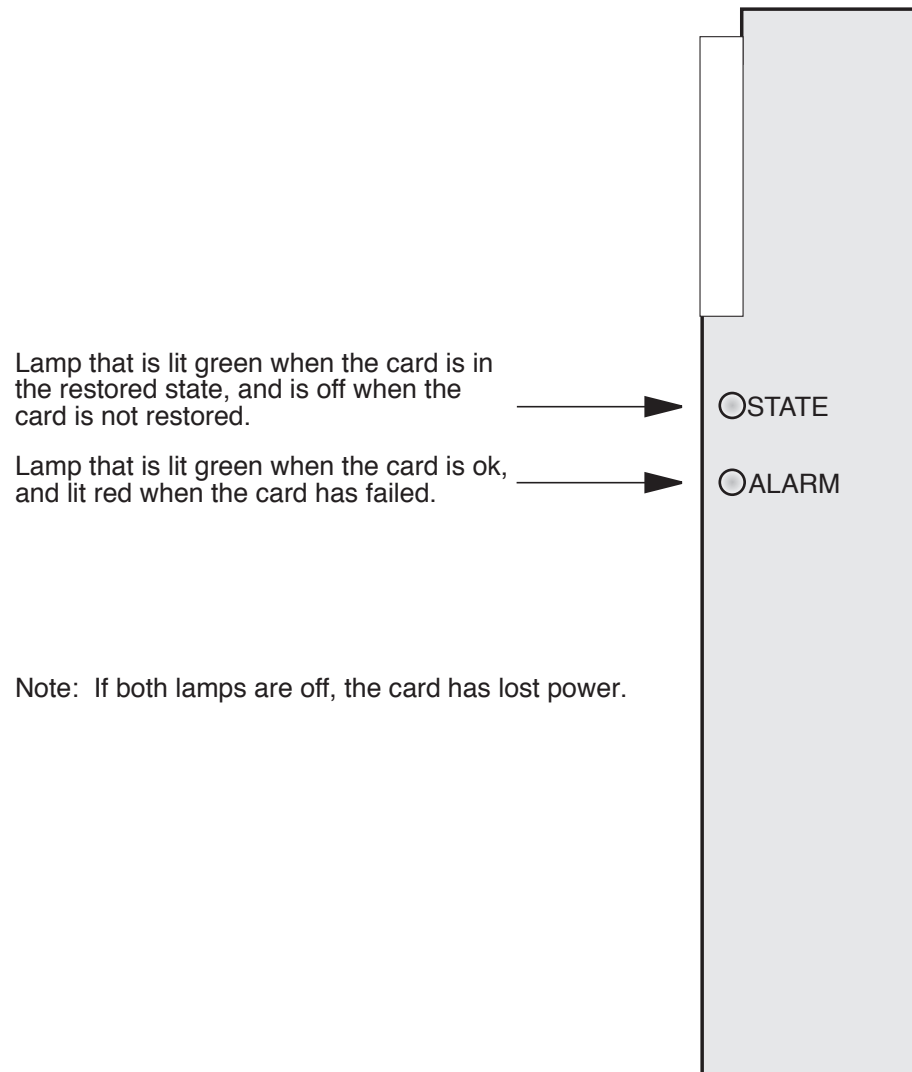


Figure 3. MAR Card Faceplate Indicators